PICO-HD01

PCB Rev. A0.3 T40E(Dual-Core)

Temperature/Humidity Test Report

Report NO:

Summary	☒ Pass ☐ Fail Note : There is/are ___ defect(s) not list in the report, please check it in the DTS Website. ☐ Pass with Deviation

Issue date	**Approval**	**Test Engineer**
2012-09-24	**Benson Lee**	**Edwin Luo**

Test item list

1. *Test item list* --- *2*
2. *Configuration of EUT* -- *3*
3. *Temp./humidity power on/off test* -- *4*
4. *Temperature variation operation test* -- *5*
5. *Cold start and hot start test*-- *6*

Testing Result

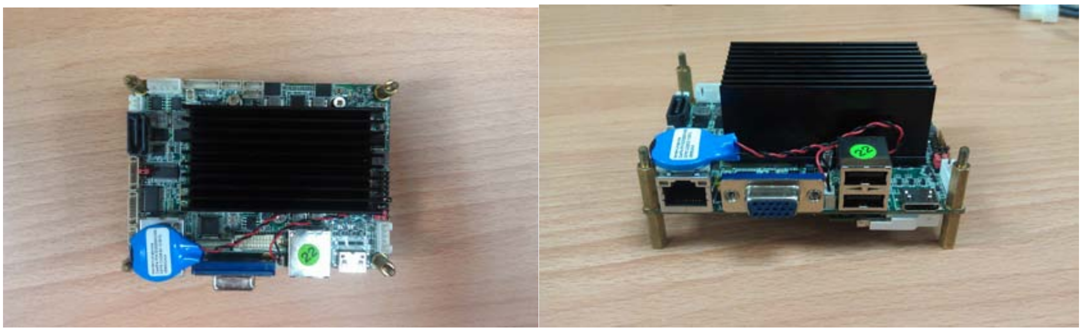
Num	Test item list	Result	Remark
1	Temp./humidity power on/off test	Pass	N/A
2	Temperature variation operation test	Pass	N/A
3	Cold start and hot start test	Pass	N/A

Configuration of EUT

Test Product: PICO-HD01 A0.2 T40E(Dual-Core)

Sample Configuration & Quantity Under Test:

1. **CPU**: AMD G-series T40E (1.0GHz Dual Core)
2. **Chipset**: G-Series A50M Chipset
3. **VGA**: AMD Radeon HD 6320
4. **Memory**: Kingston 2GB 2Rx8 PC3-10600S
5. **BIOS Reversion**: PCHDAM07
6. **CFD**: N/A
7. **SATA HDD**: Seagate ST500DM002 500GB
8. Test Software: Windows 7 x32 with SP1/ Run PassMark BurnInTest Pro v7.0 build 1004
9. Power Supply: EMACS HG2-6400P (ATX-Mode)
10. Cooler:



Temp./humidity power on/off test

Test Date: 2012-09-18~09-19

Test Site: AAEON Taichung Internal Lab

Test Standard: Reference IEC 68-2-30 Testing procedures
Test Db: Damp Heat Test

Test Equipment:

Programmable Temperature & Humidity Chamber

TERCHY. TECH. CORP.

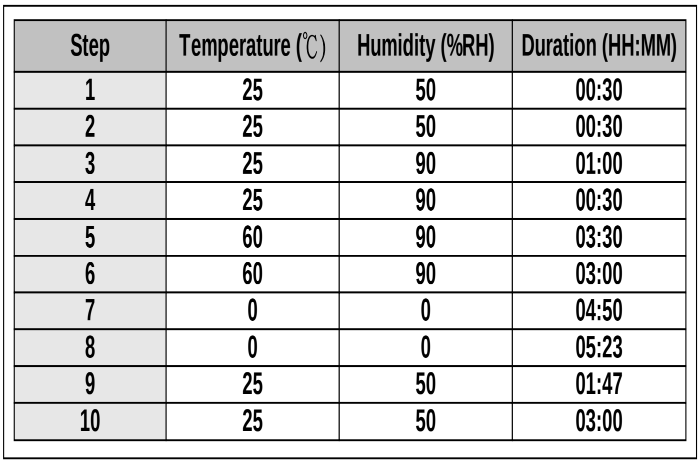
Model: MHK-225NK

Date of Calibration: 2012/03/07

Serial Number: 1000122

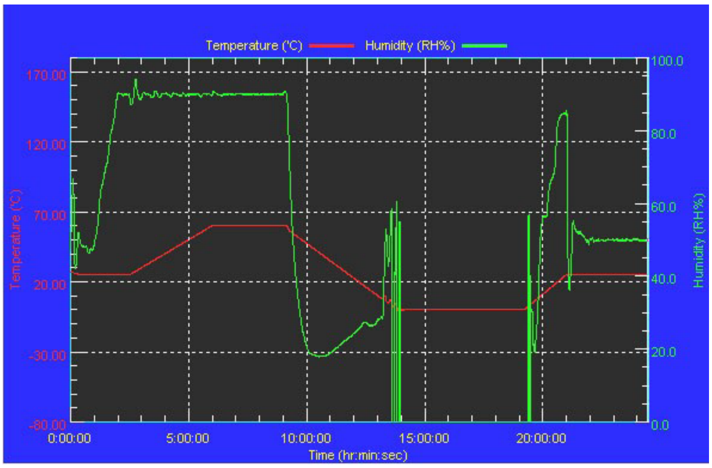
Temperature & Humidity Power On/Off Test:

Testing Specification:



Step	Temperature (℃)	Humidity (%RH)	Duration (HH:MM)
1	25	50	00:30
2	25	50	00:30
3	25	90	01:00
4	25	90	00:30
5	60	90	03:30
6	60	90	03:00
7	0	0	04:50
8	0	0	05:23
9	25	50	01:47
10	25	50	03:00

Test Curve:



Test Result:

No problem was found during the temperature & humidity power on/off test.

Test Method	Actual	Successful	Failure rate
Power On/Off	**3896/ times**	**3896/ times**	**0 %**
Note: Failure rate need to under 0.2%.			

Temperature variation operation test

Test Date: 2012-09-19~09-20

Test Site: AAEON Taichung Internal Lab

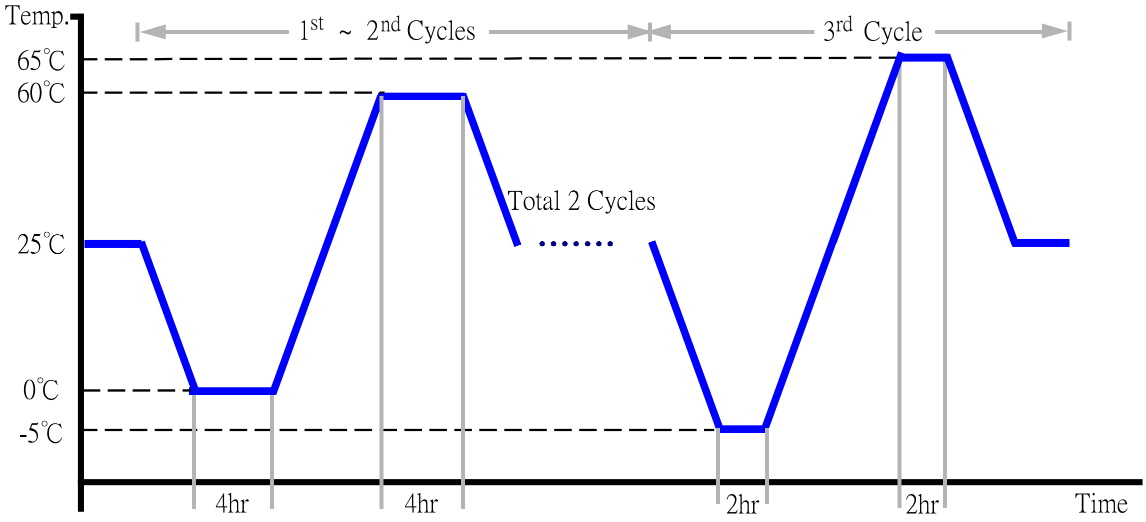
Test Standard: Reference IEC 68-2-14 Testing procedures
Test N: Change of temperature Test

Test Equipment:

Programmable Temperature & Humidity Chamber
TERCHY. TECH. CORP.
Model: MHK-225NK
Date of Calibration: 2012/03/07
Serial Number: 1000122

Temperature & Humidity Cycle Test:

1. Test Low Temperature: **0℃** (1st~2nd cycles)
   -5℃ (3rd cycle)
2. Test High Temperature: **60℃** (1st~2nd cycles)
   65℃ (3rd cycle)
3. Test dwell time: **4Hrs** (1st~2nd cycles)
   2Hrs (3rd cycle)
4. Temperature slope: **2℃/min**
5. Test cycle: **3 cycles**
6. Test Environment Curve:



Test Result:

No problem was found during the temperature variation operation test.

Cold start and hot start test

Test Date: 2012-09-21

Test Site: AAEON Taichung Internal Lab

Test Standard: Reference IEC 68-2-14 Testing procedures
Test N: Change of temperature Test

Test Equipment:

Programmable Temperature & Humidity Chamber

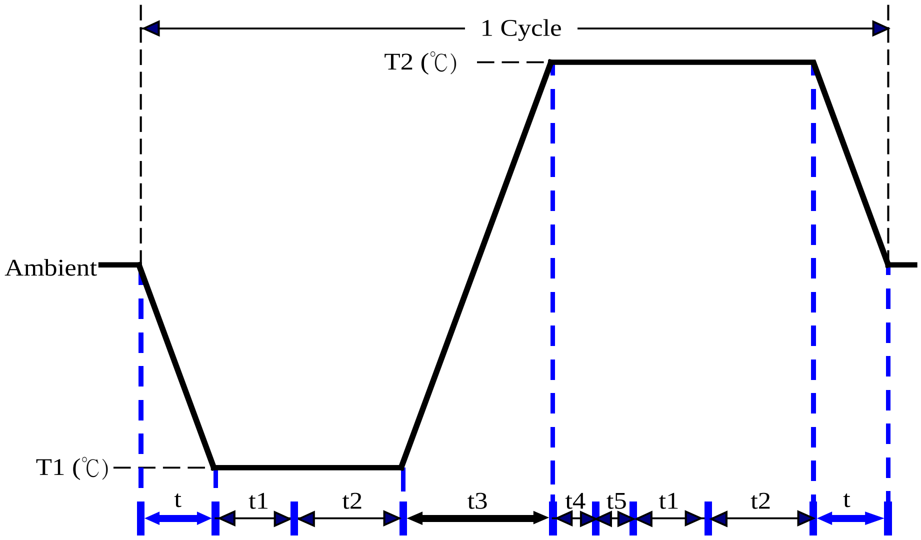
TERCHY. TECH. CORP.

Model: MHK-225NK

Date of Calibration: 2012/03/07

Serial Number: 1000122

Test Condition:



Parameters	Description
T1	-5℃
T2	65℃
t1	1 hr
t2	2 hrs
t4, t5	30 mins
t, t3	2℃/min
n (Cycle)	1

t, t3: Temperature Slope
t, t1: Power Off
t2: Power On/Off test 10 times (On 2 mins / Off 5 mins)
t5: Windows soft restart test 2 times
Test software: Windows 7 Ultimate x32 Edition

Test Result:

a. No problem was found during the cold start test.
b. No problem was found during the hot start test.